

## RADIATION TEST REPORT

PRODUCT:	AD8001SQ/QMLR
GAMMA:	50k,100k, 24Hr/ TM1019 Condition D
GAMMA SOURCE:	Co60
DOSE RATE:	9.7mRad(si)/s
FACILITIES:	University of Massachusetts @ Lowell
TESTED:	2011

The RADTEST<sup>SM</sup> DATA SERVICE is a compilation of radiation test results on Analog Devices' Space grade products. It is designed to assist customers in selecting the right product for applications where radiation is a consideration. Many products manufactured by Analog Devices, Inc. have been shown to be radiation tolerant to most tactical radiation environments. Analog Devices, Inc. does not make any claim to maintain or guarantee these levels of radiation tolerance without lot qualification test.

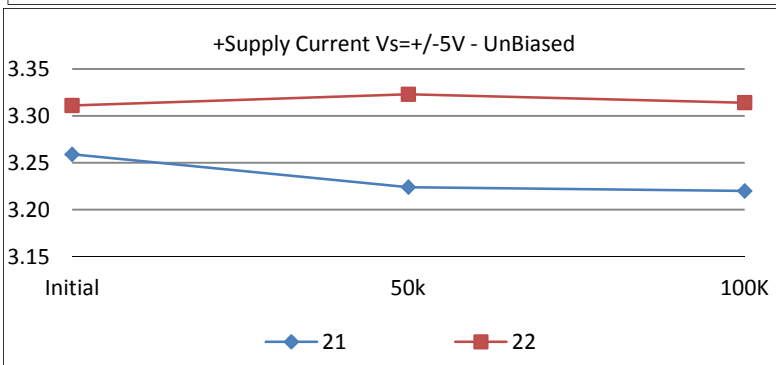
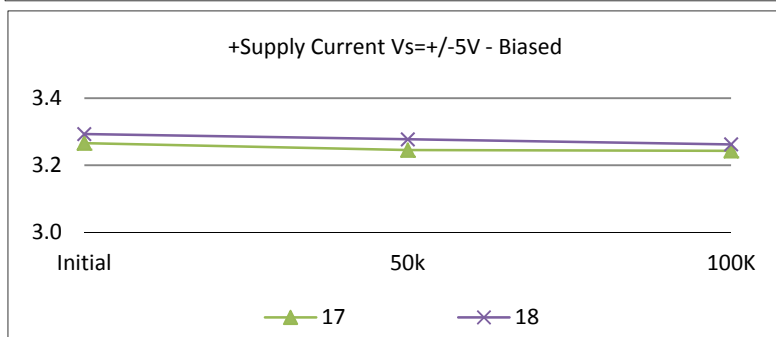
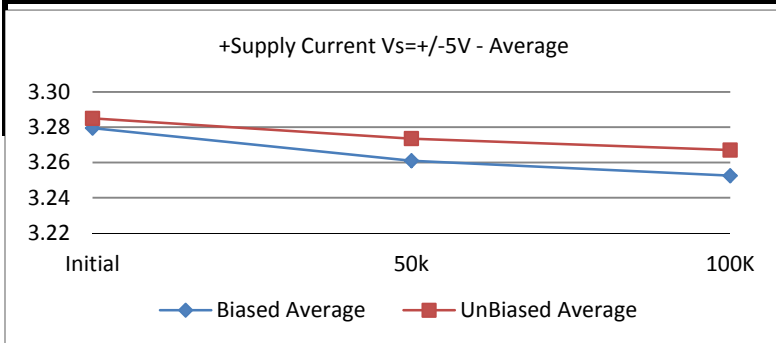
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### WARNING:

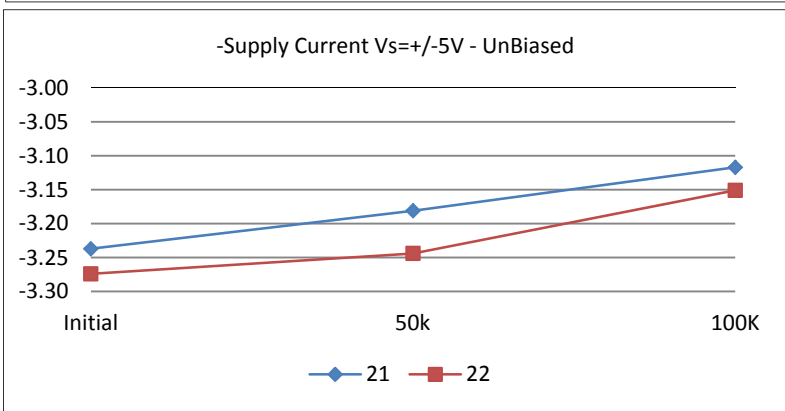
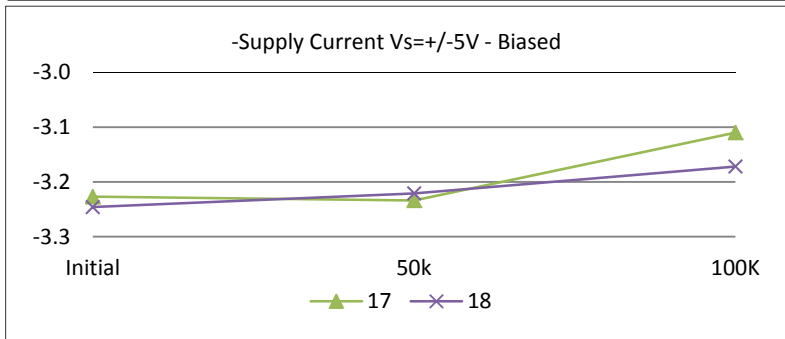
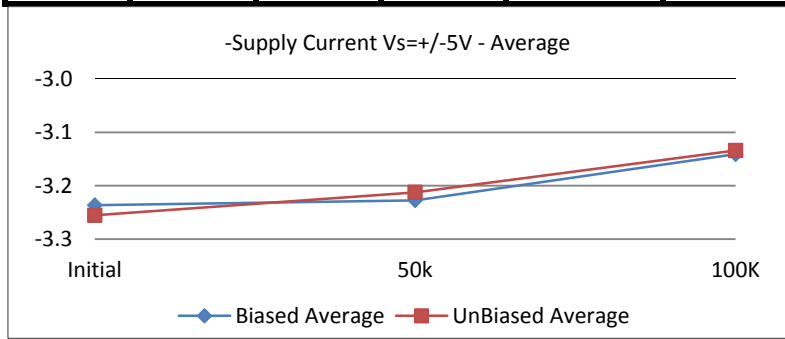
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	T# 1	IQ+ @ VS=+-5V			mA
	SN	Initial	50k	100K	25°C
<b>Control</b>	<b>20</b>	<b>3.3070</b>	<b>3.297</b>	<b>3.303</b>	<b>&lt;5.5</b>
<b>Biased</b>	<b>17</b>	3.2660	3.245	3.243	
	<b>18</b>	3.2930	3.277	3.262	
	<b>Min</b>	3.266	3.245	3.243	
	<b>Max</b>	3.293	3.277	3.262	
	<b>Average</b>	3.280	3.261	3.253	
<b>UnBiased</b>	<b>21</b>	3.259	3.224	3.220	
	<b>22</b>	3.311	3.323	3.314	
	<b>Min</b>	3.259	3.224	3.220	
	<b>Max</b>	3.311	3.323	3.314	
	<b>Average</b>	3.285	3.274	3.267	

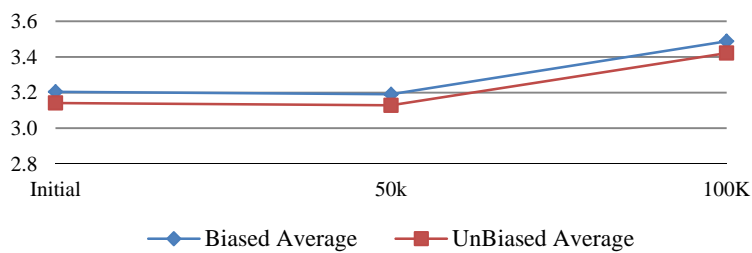


	T#2	IQ- @ VS=+-5V			mA
	SN	Initial	50k	100K	25°C
<b>Control</b>	20	-3.304	-3.267	-3.186	>-5.5
<b>Biased</b>	17	-3.227	-3.234	-3.110	
	18	-3.246	-3.221	-3.172	
	Min	-3.246	-3.234	-3.172	
	Max	-3.227	-3.221	-3.110	
	Average	-3.237	-3.228	-3.141	
<b>UnBiased</b>	21	-3.237	-3.181	-3.117	
	22	-3.274	-3.244	-3.151	
	Min	-3.274	-3.244	-3.151	
	Max	-3.237	-3.181	-3.117	
	Average	-3.256	-3.213	-3.134	

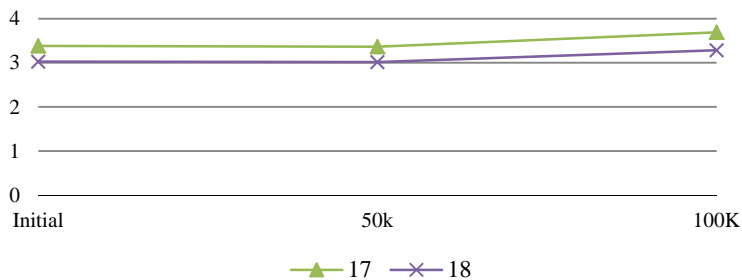


	T#3	VOS @ VS=+-5V			mV
	SN	Initial	50k	100K	25°C
<b>Control</b>	<b>20</b>	<b>3.344</b>	<b>3.359</b>	<b>3.354</b>	<b>Limit</b>
<b>Biased</b>	<b>17</b>	3.383	3.366	3.692	<b>&lt;6.5</b>
	<b>18</b>	3.026	3.015	3.284	
	<b>Min</b>	3.026	3.015	3.284	
	<b>Max</b>	3.383	3.366	3.692	
	<b>Average</b>	3.205	3.191	3.488	
<b>UnBiased</b>	<b>21</b>	3.538	3.530	3.842	
	<b>22</b>	2.745	2.727	3.001	
	<b>Min</b>	2.745	2.727	3.001	
	<b>Max</b>	3.538	3.530	3.842	
	<b>Average</b>	3.142	3.129	3.422	

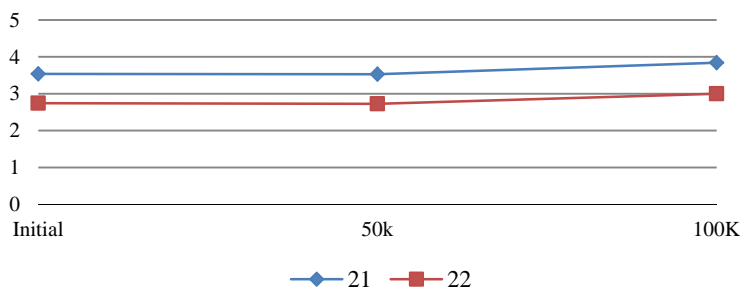
VOS @ VS=+-5V - Average



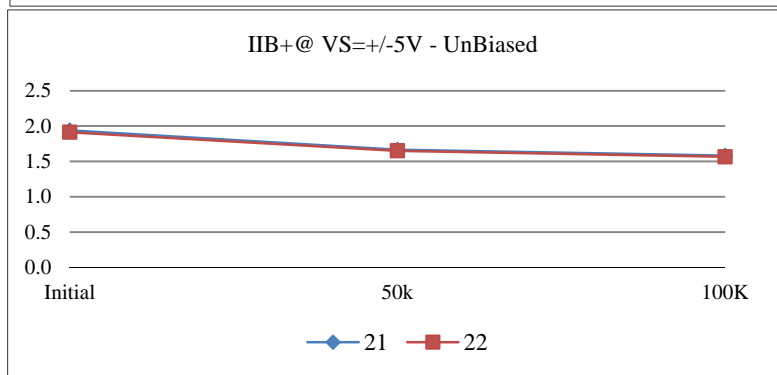
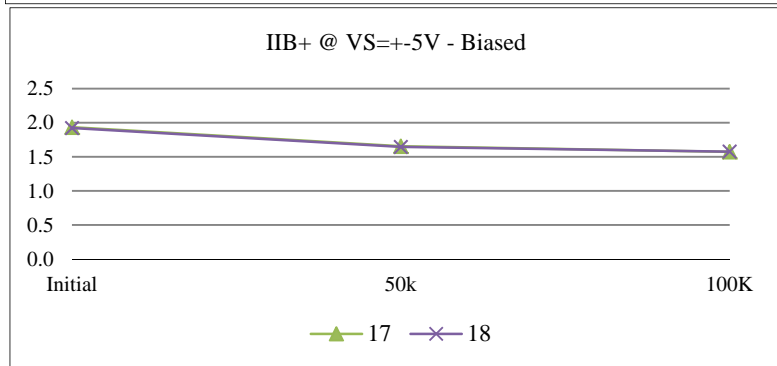
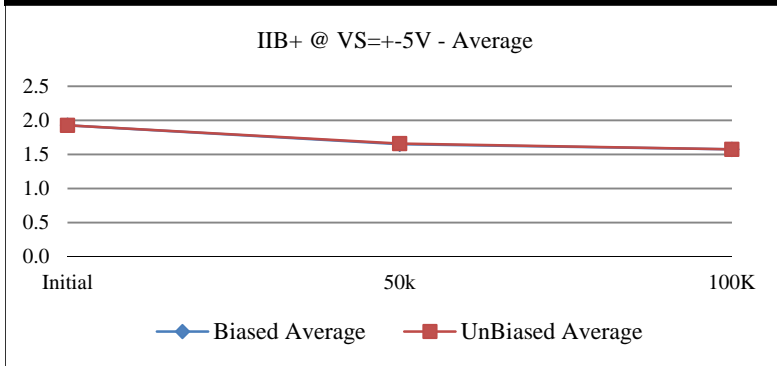
VOS @ VS=+-5V - Biased



-Output Voltage Swing RI=0.6k - UnBiased



	T#4	IIB+ @ VS=+-5V			uA
	SN	Initial	50k	100K	25°C
<b>Control</b>	<b>20</b>	<b>1.920</b>	<b>1.778</b>	<b>1.769</b>	<b>Limit</b>
<b>Biased</b>	<b>17</b>	1.933	1.654	1.573	+/-10
	<b>18</b>	1.922	1.645	1.576	
	<b>Min</b>	1.922	1.645	1.573	
	<b>Max</b>	1.933	1.654	1.576	
	<b>Average</b>	1.928	1.650	1.575	
<b>UnBiased</b>	<b>21</b>	1.940	1.666	1.582	
	<b>22</b>	1.913	1.651	1.566	
	<b>Min</b>	1.913	1.651	1.566	
	<b>Max</b>	1.940	1.666	1.582	
	<b>Average</b>	1.927	1.659	1.574	



	T#5	IIB- @ VS=+-5V			uA
	SN	Initial	50k	100K	25°C
<b>Control</b>	<b>20</b>	<b>7.683</b>	<b>7.436</b>	<b>7.296</b>	<b>Limit</b>
<b>Biased</b>	<b>17</b>	7.361	3.039	1.766	+/-25
	<b>18</b>	4.865	-0.036	-4.768	
	<b>Min</b>	4.865	-0.036	-4.768	
	<b>Max</b>	7.361	3.039	1.766	
	<b>Average</b>	6.113	1.502	-1.501	
<b>UnBiased</b>	<b>21</b>	7.472	3.039	1.768	
	<b>22</b>	4.626	-1.046	-2.801	
	<b>Min</b>	4.626	-1.046	-2.801	
	<b>Max</b>	7.472	3.039	1.768	
	<b>Average</b>	6.049	0.997	-0.517	

